

## 240A, 40V N-CHANNEL POWER MOSFET

## GENERAL DESCRIPTION

The SFA4024T uses advanced Process technology and design to provide excellent  $R_{DS(on)}$  with low gate charge.

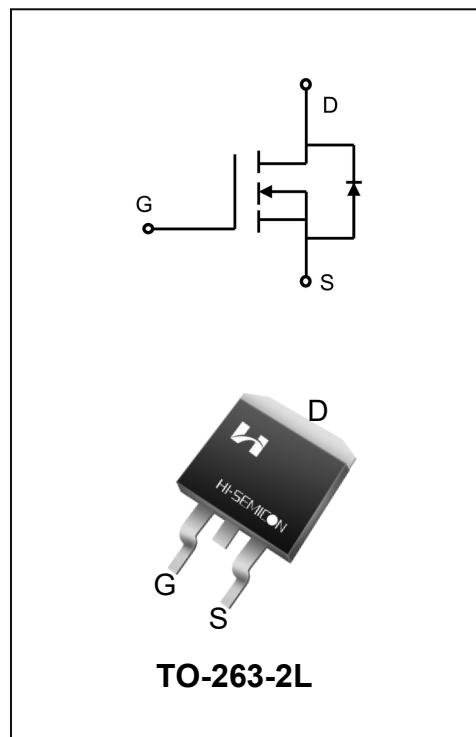
It can be used in a wide variety applications.

## Features

- ◆  $V_{DS}=40V, I_D=240A$
- ◆  $R_{DS(on)}$   
TYP:  $2.0m\Omega @ V_{GS}=10V, I_D=60A$

## Applications

- ◆ Load switch
- ◆ Power switch applications



## ORDERING INFORMATION

Part No.	Package	Marking	Material	Packing
SFA4024T	TO-263-2L	SFA4024T	Pb Free	Reel

ABSOLUTE MAXIMUM RATINGS ( $T_J=25^\circ\text{C}$  unless otherwise noted)

Characteristics		Symbol	Ratings		Unit
Drain-Source Voltage		$V_{DS}$	40		V
Gate-Source Voltage		$V_{GS}$	$\pm 20$		V
Drain Current	$T_C = 25^\circ\text{C}$	$I_D$	240		A
	$T_C = 100^\circ\text{C}$		150		
Drain Current Pulsed(Note 1)		$I_{DM}$	960		A
Power Dissipation( $T_C=25^\circ\text{C}$ ) -Derate above $25^\circ\text{C}$		$P_D$	250		W
			2.0		
Single Pulsed Avalanche Energy (Note 2)		$E_{AS}$	611		mJ
Operation Junction Temperature Range		$T_J$	-55~+150		$^\circ\text{C}$
Storage Temperature Range		$T_{stg}$	-55~+150		$^\circ\text{C}$
Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		$TL$	300		$^\circ\text{C}$

## THERMAL CHARACTERISTICS

Characteristics	Symbol	MAX			Unit
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	0.5			$^\circ\text{C}/\text{W}$
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	62.5			$^\circ\text{C}/\text{W}$

## ELECTRICAL CHARACTERISTICS

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Off Characteristics						
Drain -Source Breakdown Voltage	$B_{VDSS}$	$V_{GS}=0\text{V}, I_D=250\mu\text{A}$	40	--	--	V
Drain-Source Leakage Current	$I_{DSS}$	$V_{DS}=40\text{V}, V_{GS}=0\text{V}$	--	--	1.0	$\mu\text{A}$
Gate-Source Leakage Current	$I_{GSS}$	$V_{GS}=20\text{V}, V_{DS}=0\text{V}$	--	--	100	nA
Gate-Source Leakage Current	$I_{GSS}$	$V_{GS}=-20\text{V}, V_{DS}=0\text{V}$	--	--	-100	nA
On Characteristics						
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{GS}=V_{DS}, I_D=250\mu\text{A}$	2.2	--	3.8	V
Static Drain- Source On State Resistance	$R_{DS(\text{on})}$	$V_{GS}=10\text{V}, I_D=60\text{A}$	--	2.0	2.5	$\text{m}\Omega$
Dynamic Characteristics						
Gate Resistance	$R_g$	$V_{GS}=0\text{V}; f=1.0\text{MHz}$		4.0		$\Omega$
Input Capacitance	$C_{iss}$	$V_{DS}=25\text{V}$	--	5620	--	$\text{pF}$
Output Capacitance	$C_{oss}$		--	783	--	
Reverse Transfer Capacitance	$C_{rss}$		f=1.0MHz	518	--	
Switching Characteristics						
Turn-on Delay Time	$t_{d(on)}$	$V_{DD}=20\text{V}; V_{GS}=10\text{V}$ $R_G=2.7\Omega; I_D=30\text{A}$ (Note 3.4)	--	26	--	ns
Turn-on Rise Time	$t_r$		--	88	--	
Turn-off Delay Time	$t_{d(off)}$		--	135	--	
Turn-off Fall Time	$t_f$		--	116	--	

Total Gate Charge	$Q_g$	$V_{DS}=32V, I_D=50A$ $V_{GS}=10V$ (Note 3.4)	--	109	--	nc
Gate-Source Charge	$Q_{gs}$		--	35	--	
Gate-Drain Charge	$Q_{gd}$		--	32	--	

## SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Continuous Source Current	$I_s$	Integral Reverse P-N Junction Diode in the MOSFET	--	--	240	A
Pulsed Source Current	$I_{SM}$		--	--	960	
Diode Forward Voltage	$V_{SD}$	$I_s=50A, V_{GS}=0V$	--	--	1.2	V
Reverse Recovery Time	$T_{rr}$	$I_F=50A, V_{GS}=0V$ $dI/dt=100A/\mu s$	--	30	--	ns
Reverse Recovery Charge	$Q_{rr}$		--	0.03	--	$\mu C$

1. Pulse width limited by maximum junction temperature

2. L=1.0mH  $V_{DD}=38V$ ,  $V_G=10V$ ,  $R_G=25\Omega$ , starting  $T_J=25^\circ C$ 3. Pulse Test: Pulse width  $\leq 300\mu s$ , Duty cycle  $\leq 2\%$ 

4. Essentially independent of operating temperature

## Typical Performance Characteristics

Figure 1. Output Characteristics

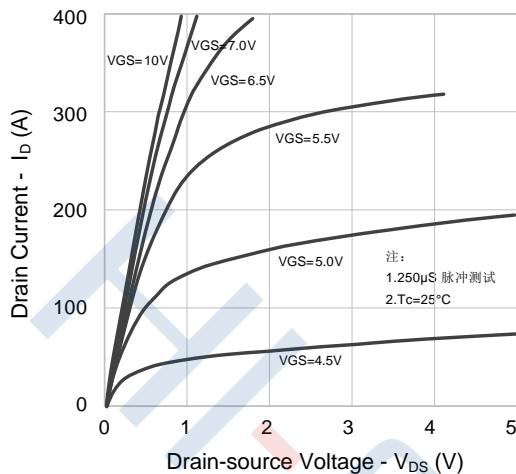


Figure 2. Transfer Characteristics

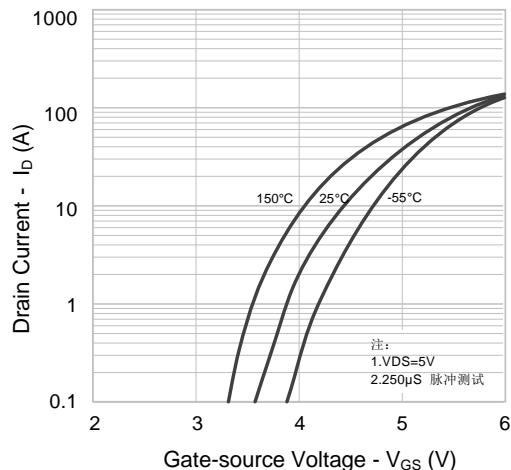


Figure 3. On-resistance vs. Drain Current

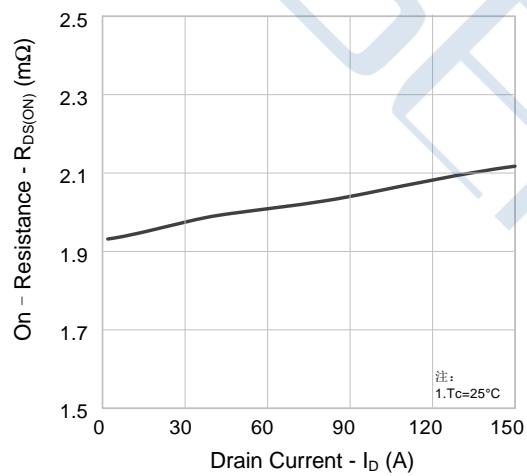


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

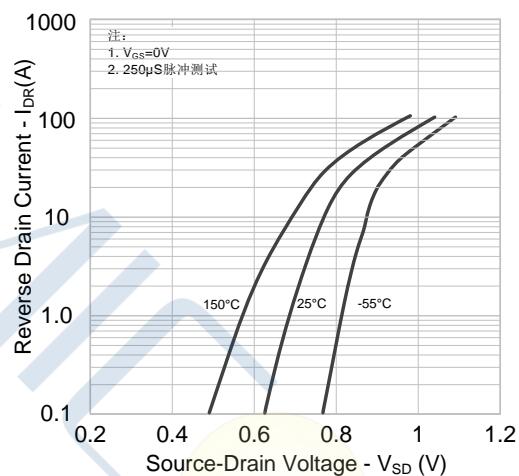


Figure 5. Capacitance Characteristics

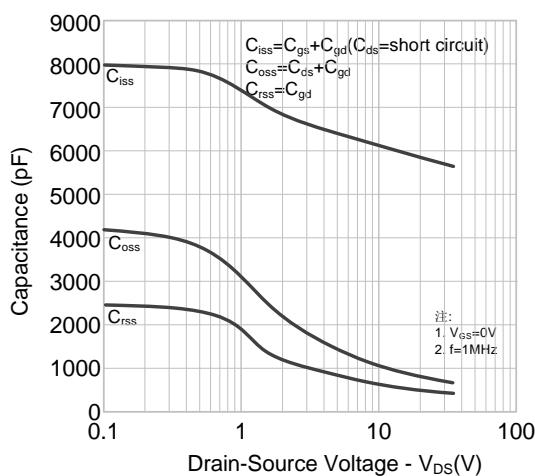
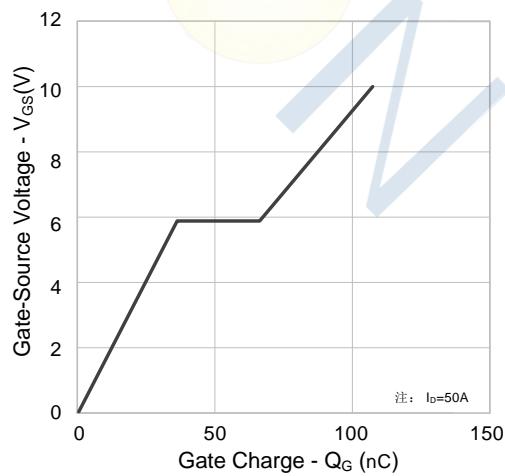


Figure 6. Gate Charge



## Typical Performance Characteristics

Figure 7. Breakdown Voltage vs. Temperature Characteristics

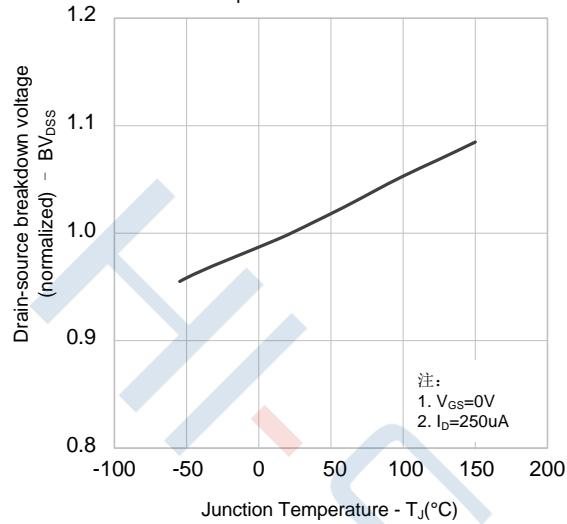


Figure 8. On-resistance vs. Temperature Characteristics

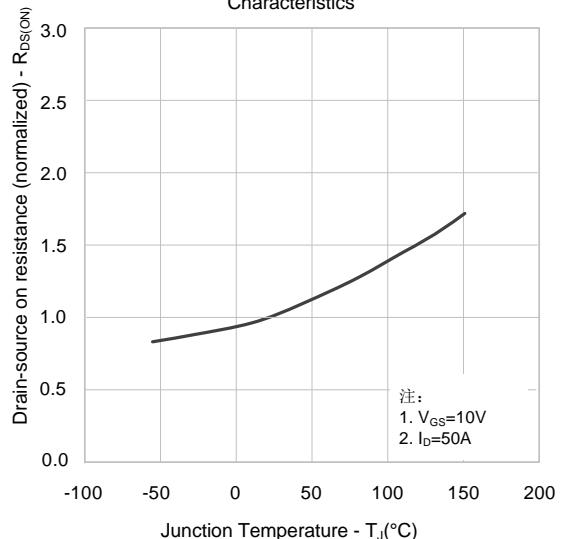
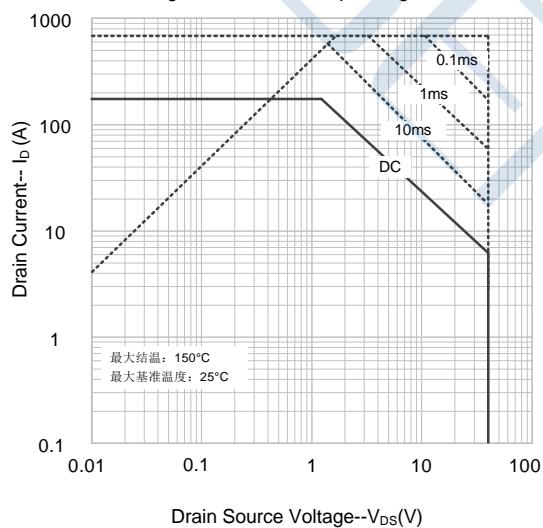
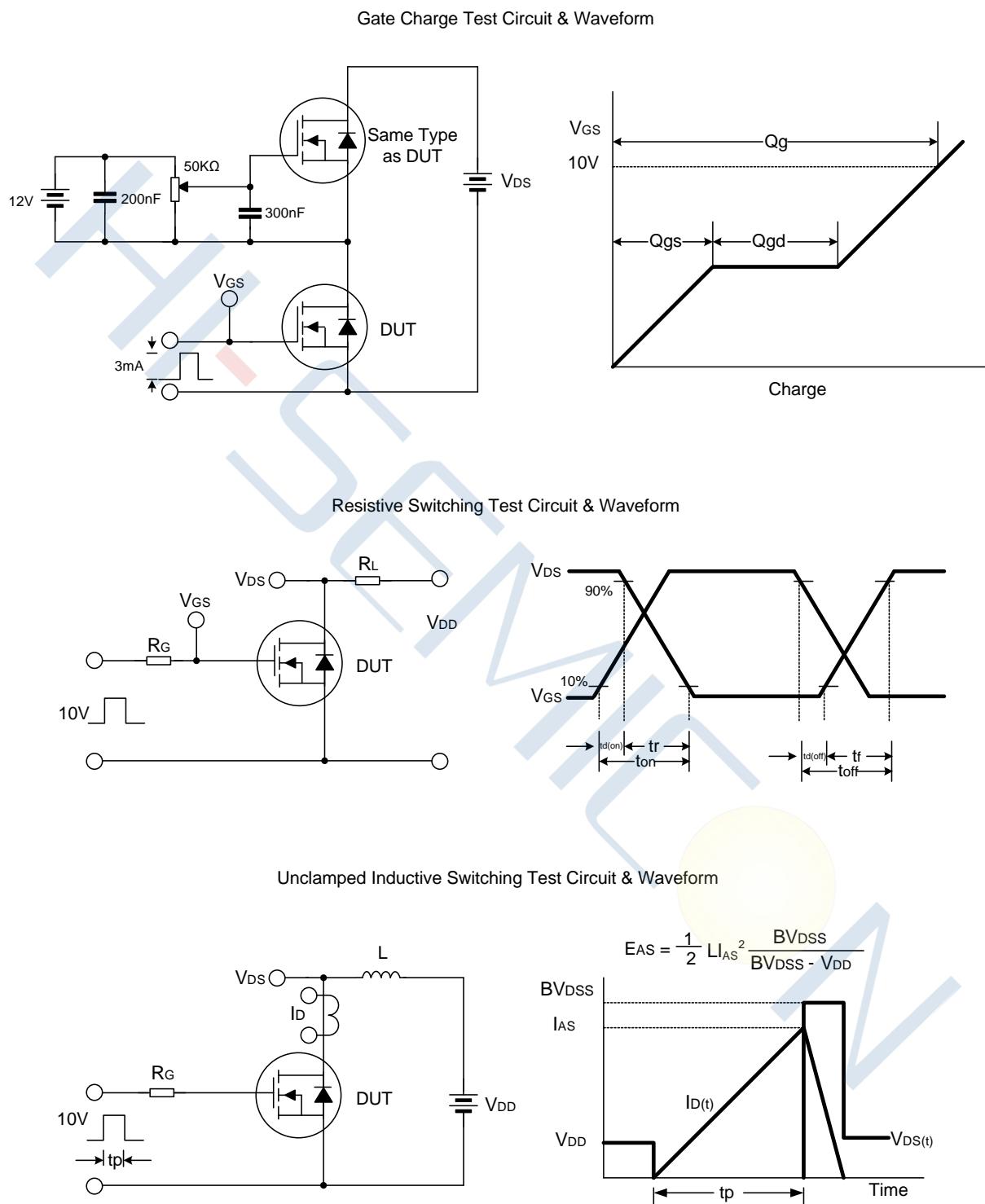


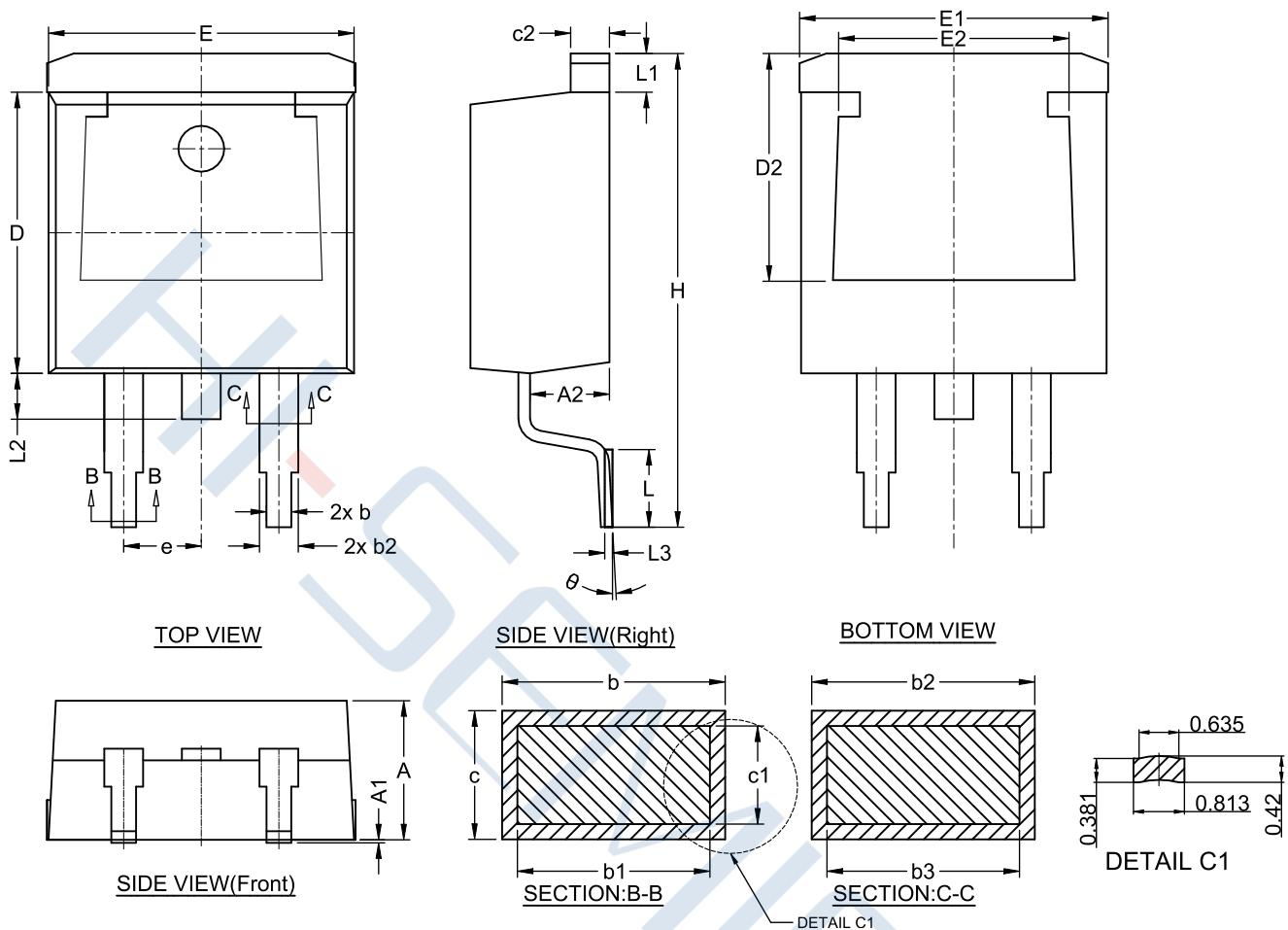
Figure 9. Max. Safe Operating Area



### Test Circuit



## Package Dimensions of TO-263-2L



DIM SYMBOL	MIN.	NOM.	MAX.
A	4.450	4.550	4.650
A1	0.000	—	0.150
A2	2.500	2.600	2.700
b	0.753	0.853	0.953
b1	0.713	0.813	0.913
b2	1.210	1.310	1.410
b3	1.170	1.270	1.370
c	0.330	0.421	0.521
c1	0.281	0.381	0.481
c2	1.210	1.310	1.410
D	9.100	9.200	9.300
D2	7.215	7.415	7.615
E	9.900	10.000	10.100
E1	9.900	10.100	10.300
E2	7.341	7.541	7.741
e	2.540 BSC.		
H	15.300	15.500	15.700
L	2.340	2.540	2.740
L1	1.066	1.266	1.466
L2	1.400	1.500	1.600
L3	0.254 BSC.		
θ	0°	---	5°

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